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## Refine Search

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5216275	135

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L9

Refine Search

Recall Text  Clear  Interrupt 

### Search History

**DATE:** Thursday, January 13, 2005 [Printable Copy](#) [Create Case](#)

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<i>side by side</i>			
	<i>DB=USPT; PLUR=YES; OP=OR</i>		
<u>L9</u>	5216275	135	<u>L9</u>
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<u>L7</u>	L6	0	<u>L7</u>
<i>DB=DWPI; PLUR=YES; OP=OR</i>			
<u>L6</u>	L5	0	<u>L6</u>
<i>DB=JPAB; PLUR=YES; OP=OR</i>			
<u>L5</u>	L4	0	<u>L5</u>
<i>DB=EPAB; PLUR=YES; OP=OR</i>			
<u>L4</u>	L3	0	<u>L4</u>
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<u>L3</u>	L2	0	<u>L3</u>
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<u>L2</u>	L1	0	<u>L2</u>

*DB=USPT; PLUR=YES; OP=OR*

L1 "trench gate" and "field shield"

1 L1

END OF SEARCH HISTORY